


<b>Search Notes</b>  	<b>Application/Control No.</b>  10660698	<b>Applicant(s)/Patent Under Reexamination</b>  OHISHI ET AL.
	<b>Examiner</b>  Fikremariam Yalew	<b>Art Unit</b>  2136

SEARCHED			
Class	Subclass	Date	Examiner
380	200	11/9/2008	FA
713	182	11/9/2008	FA

SEARCH NOTES		
Search Notes	Date	Examiner
Upadeted East search,NPL search,Inventor search	11/9/2008	FA

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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